

UNITED STATES PATENT AND TRADEMARK OFFICE

---

BEFORE THE PATENT TRIAL AND APPEAL BOARD

---

TAIWAN SEMICONDUCTOR MANUFACTURING CO., LTD,  
Petitioner,

v.

GODO KAISHA IP BRIDGE 1,  
Patent Owner.

---

Case IPR2017-01843<sup>1</sup>  
Patent 7,893,501

---

**PATENT OWNER'S SUR-REPLY  
PURSUANT TO PAPER NO. 40**

---

<sup>1</sup> IPR2017-01844 has been consolidated with this proceeding. *See* Paper 10 at 3.

**TABLE OF CONTENTS**

I. PETITIONER’S IMPROPER NEW REPLY ARGUMENT FAILS.....1

    A. Silicon Oxide Spacers Cannot Be Thermally Grown “On Top of  
        The Silicide Layer” .....1

    B. Misra Teaches Only Silicon Nitride Spacers 23 .....2

II. PATENT OWNER MAINTAINS ITS IMPROPER NEW  
    ARGUMENT OBJECTION.....4

## TABLE OF AUTHORITIES

### CASES

|  |   |
|--|---|
| <i>Ariosa Diagnostics v. Verinata Health, Inc.</i> (“Ariosa”),<br>805 F.3d 1359 (Fed. Cir. 2015) ..... | 4 |
| <i>In re: NuVasive, Inc.</i> (“NuVasive”),<br>841 F.3d 966 (Fed. Cir. 2016) .....                      | 4 |

## I. PETITIONER’S IMPROPER NEW REPLY ARGUMENT FAILS

The Reply cited Misra 6:54-58 (not cited in the Petition) to support the new argument that Misra teaches that spacers 23 can be “made of a thermally grown silicon dioxide<sup>2</sup> rather than silicon nitride.” Reply at 4 (citing Ex. 1232, ¶10 where Shanfield quotes Misra 6:54-58 in full and opines “[t]his disclosure [Misra 6:54-58] refers to a silicon oxide formed *on top of* the silicide layer” from “thermally-driven diffusion of excess silicon in the silicide.”). Petitioner and Shanfield are wrong about what this newly cited section of Misra discloses.

### A. Silicon Oxide Spacers Cannot Be Thermally Grown “On Top of The Silicide Layer”

First, spacers 23 *cannot be formed “on top of silicide layer”* 18 because the top of silicide layer 18 is not exposed when spacers 23 are formed. Misra, Figs. 5-7. As shown in Figs. 2-3, “*silicide layer 18 within the opening 24 is etched away*” and “*remove[d]*” so sacrificial oxide 25 can thermally grow on the silicon substrate. *Id.* at 5:43-67, 6:34-36. Spacers 23 are formed “on top of the *sacrificial oxide 25*” in locations from which silicide layer 18 was removed—not “on top of the silicide layer” as Shanfield erroneously alleged. *Id.* at 6:37-42.

---

<sup>2</sup> The Reply and Ex. 1232 refer to silicon oxide and silicon dioxide. Both would be understood by a POSA to refer to SiO<sub>2</sub> in this field. Regardless, arguments in this brief apply to whichever oxide of silicon allegedly replaces silicon nitride (“SiN”).

Second, silicon oxide spacers cannot grow by “thermally-driven diffusion” on oxide 25. *See* Sec. I.B. Thus, “thermally-driven diffusion” cannot form silicon oxide spacers 23 in Misra’s spacer embodiment (Fig. 7). *Compare* Ex. 1232, ¶10.

Third, SiN layer 20 “is deposited *overlying* ... silicide [] 18.” Misra 5:20-22, Figs. 2-7. Because SiN is a diffusion barrier, *preventing oxidation of the silicide*, silicon oxide cannot thermally grow on top of silicide 18 which is covered by SiN.

Fourth, Shanfield mischaracterizes Misra as disclosing an inoperable device. If spacers 23 were somehow thermally grown silicon oxide on top of silicide layer 18 as Shanfield suggests (*i.e.*, if in Fig. 7 spacers 23 were silicon oxide, and elements 25 were silicide), the silicide under the spacers would electrically connect (short) gate 28b to source 26 and drain 28, rendering the device inoperable. *Id.* 6:49-54 (spacers required to isolate the gate from silicide).

### **B. Misra Teaches Only Silicon Nitride Spacers 23**

“*After* formation of the spacers,” ion implantation is used to dope region 31. Misra 6:42-58. A POSA would have understood this also “*dopes*” spacers 23 and *decreases their ability to isolate the gate*. Misra teaches the damaged SiN spacers may be replaced with (1) *new* SiN spacers or (2) *new* SiN spacers “composited with a sidewall thermal growth” (*i.e.*, prior to re-depositing SiN spacers, silicon oxide is thermally grown on oxide 25 and exposed portions of the lateral surfaces of silicide 18). In both cases, *silicon nitride* covers the sides of Misra’s gate 28b.

# Explore Litigation Insights

Docket Alarm provides insights to develop a more informed litigation strategy and the peace of mind of knowing you're on top of things.

## Real-Time Litigation Alerts



Keep your litigation team up-to-date with **real-time alerts** and advanced team management tools built for the enterprise, all while greatly reducing PACER spend.

Our comprehensive service means we can handle Federal, State, and Administrative courts across the country.

## Advanced Docket Research



With over 230 million records, Docket Alarm's cloud-native docket research platform finds what other services can't. Coverage includes Federal, State, plus PTAB, TTAB, ITC and NLRB decisions, all in one place.

Identify arguments that have been successful in the past with full text, pinpoint searching. Link to case law cited within any court document via Fastcase.

## Analytics At Your Fingertips



Learn what happened the last time a particular judge, opposing counsel or company faced cases similar to yours.

Advanced out-of-the-box PTAB and TTAB analytics are always at your fingertips.

## API

Docket Alarm offers a powerful API (application programming interface) to developers that want to integrate case filings into their apps.

## LAW FIRMS

Build custom dashboards for your attorneys and clients with live data direct from the court.

Automate many repetitive legal tasks like conflict checks, document management, and marketing.

## FINANCIAL INSTITUTIONS

Litigation and bankruptcy checks for companies and debtors.

## E-DISCOVERY AND LEGAL VENDORS

Sync your system to PACER to automate legal marketing.